What is claimed is:

1   1. A method for determining power of a modulated signal, comprising:

2   applying the modulated signal to a wavelength meter to provide a frequency transformed

3   interferogram representing the modulated signal by a plurality of consecutive frequency bins,

4   each frequency bin in the plurality of frequency bins having a corresponding bin value;

5   designating a bin range within the frequency transformed interferogram; and

6   summing a series of bin values within the frequency transformed interferogram over the

7   designated bin range to provide a sum that represents the power of the modulated signal to a

8   predetermined accuracy.

2   2. The method of claim 1 wherein designating the bin range within the frequency

    transformed interferogram includes mapping a series of signal characteristics to a corresponding

    series of bin spans and enabling a selection of one signal characteristic from the series of signal

    characteristics, wherein in response to selection of the one signal characteristic from the series

5   of signal characteristics establishing the designated bin range as having a bin span that

6   corresponds to the selected one signal characteristic defined by the mapping of the series of

7   signal characteristics to the corresponding series of bin spans, and being centered about a center

8   bin within the frequency transformed interferogram.

1   3. The method of claim 2 wherein the series of signal characteristics indicates at least one

2   of a plurality of modulation formats for the modulated signal, a plurality of channel spacings for

3   optical carriers of the modulated signal, and a plurality of frequency spans that encompass

4   modulation of the modulated signal.

1   4. The method of claim 2 wherein the mapping of the series of signal characteristics to

2   the corresponding series of bin spans is established empirically.

1   5. The method of claim 3 wherein the mapping of the series of signal characteristics to

2   the corresponding series of bin spans is established empirically.

1   6. The method of claim 2 wherein the mapping is established according to a computer

2   simulation of the wavelength meter providing the frequency transformed interferogram.

1   7. The method of claim 3 wherein the mapping is established according to a computer

2   simulation of the wavelength meter providing the frequency transformed interferogram.

1   8. The method of claim 2 wherein enabling a selection of the one signal characteristic

2   from the series of signal characteristics includes presenting a display menu representing the series

3   of signal characteristics and providing for the selection of the one signal characteristic from the

4   display menu via a pointing device.

1   9. The method of claim 3 wherein enabling a selection of the one signal characteristic

2   from the series of signal characteristics includes presenting a display menu representing the series

3   of signal characteristics and providing for the selection of the one signal characteristic from the

4   display menu via a pointing device.

1   10. The method of claim 2 wherein enabling the selection of one signal characteristic

2   from the series of signal characteristics is performed automatically based on attributes of the

3   frequency transformed interferogram representing the modulated signal.

1   11. The method of claim 3 wherein the selection of the one signal characteristic from the

2   series of signal characteristics is performed automatically based on attributes of the frequency

3   transformed interferogram representing the modulated signal.

1   12. The method of claim 10 wherein performing the selection of the one signal

2   characteristic from the series of signal characteristics automatically includes assessing bin values

3   corresponding to multiple frequency bins within the frequency transformed interferogram to

4   determine at least one of a modulation format of the modulated signal applied to the wavelength

5   meter and a frequency spacing of optical carriers of the modulated signal applied to the

6   wavelength meter.

1   13. The method of claim 1 wherein designating a bin range within the frequency

2   transformed interferogram is performed automatically based on attributes of the frequency

3   transformed interferogram.

1   14. The method of claim 13 wherein designating the bin range includes accessing bin

2   values corresponding to multiple frequency bins within the frequency transformed interferogram

3   and based on the accessed bin values establishing the bin range to be centered about a center bin

4   within the frequency transformed interferogram and to have a bin span within the frequency

5   transformed interferogram that includes a predesignated number of sidebands on each side of the

6   center bin, the predesignated number of sidebands representing modulation of the modulated

7   signal.

1   15. The method of claim 13 wherein designating the bin range includes accessing bin

2   values corresponding to multiple frequency bins within the frequency transformed intererogram

3   and based on the accessed bin values, establishing the bin range to be centered about a center bin

4   within the frequency transformed interferogram and to have a bin span within the frequency

5   transformed interferogram that spans a sufficient number of frequency bins on each side of the

6   center bin so that any bin span wider than the bin span has bin values that do not exceed a

7   designated threshold of the frequency transformed interferogram.